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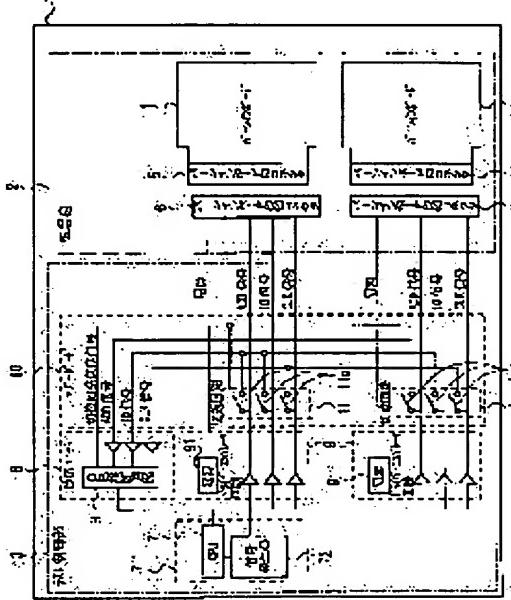
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(54) TEST BURN-IN DEVICE AND METHOD OF CONTROLLING TEST BURN- IN DEVICE

(57)Abstract:

PROBLEM TO BE SOLVED: To provide a test burn-in device for making a simple, effective self diagnostic test possible to be performed, and a method of controlling the test burn-in device.

SOLUTION: A diagnostic unit 8 is mounted on a mother board 10 within a test control part 3, and various kinds of signals outputted from one driver.comparator circuit 9 among various kinds of signals outputted from plural driver.comparator circuits 9 are inputted in a self diagnostic circuit 81. After the diagnosis of various kinds of signals outputted from the driver.comparator circuit 9, various kinds of signals outputted from another driver.comparator circuit 9 are switched with a switching circuit 11 so as to be input in the self diagnostic circuit 81 to conductor diagnosis, and by repeating this procedure, the self diagnostic test is conducted to all of the driver.comparator circuits 9 within the test burn-in device 1.



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